Product data sheet

1. General description

The 74ABT08 high-performance BiCMOS device combines low static and dynamic power dissipation with high speed and high output drive.

The 74ABT08 is a quad 2-input AND gate.

2. Features and benefits

- Latch-up protection exceeds 500 mA per JESD78B class II level A
- ESD protection:
 - HBM JESD22-A114F exceeds 2000 V
 - MM JESD22-A115-A exceeds 200 V
- Multiple package options
- Specified from –40 °C to +85 °C

3. Ordering information

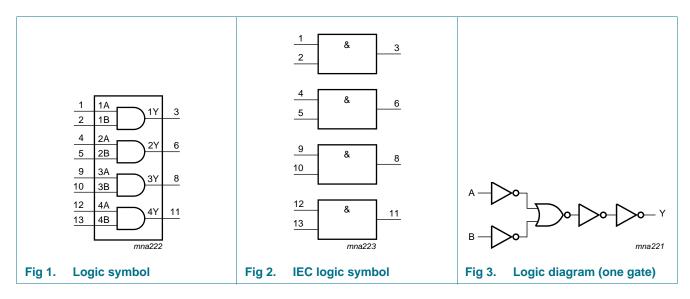
Table 1.Ordering information

Type number	Package						
	Temperature range	Name	Description	Version			
74ABT08N	–40 °C to +85 °C	DIP14	plastic dual in-line package; 14 leads (300 mil)	SOT27-1			
74ABT08D	–40 °C to +85 °C	SO14	plastic small outline package; 14 leads; body width 3.9 mm	SOT108-1			
74ABT08DB	–40 °C to +85 °C	SSOP14	plastic shrink small outline package; 14 leads; body width 5.3 mm	SOT337-1			
74ABT08PW	–40 °C to +85 °C	TSSOP14	plastic thin shrink small outline package; 14 leads; body width 4.4 mm	SOT402-1			



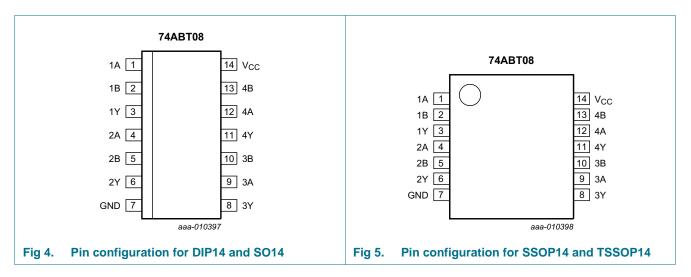
74ABT08 Quad 2-input AND gate

4. Functional diagram



5. Pinning information

5.1 Pinning



5.2 Pin description

Table 2. Pin description		
Symbol	Pin	Description
1A to 4A	1, 4, 9, 12	data input
1B to 4B	2, 5, 10, 13	data input
1Y to 4Y	3, 6, 8, 11	data output
GND	7	ground (0 V)
V _{cc}	14	supply voltage

6. Functional description

Table 3. Function table^[1]

Input		Output
nA	nB	nY
L	X	L
Х	L	L
н	Н	Н

[1] H = HIGH voltage level; L = LOW voltage level; X = don't care.

7. Limiting values

Table 4.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{CC}	supply voltage			-0.5	+7.0	V
VI	input voltage		<u>[1]</u>	-1.2	+7.0	V
Vo	output voltage	output HIGH or LOW	<u>[1]</u>	-0.5	+5.5	V
I _{IK}	input clamping current	V _I < 0 V		-18	-	mA
I _{OK}	output clamping current	V _O < 0 V		-50	-	mA
lo	output current	output in LOW-state		-	40	mA
Tj	junction temperature		[2]	-	150	°C
T _{stg}	storage temperature			-65	+150	°C

[1] The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

[2] The performance capability of a high-performance integrated circuit in conjunction with its thermal environment can create junction temperatures which are detrimental to reliability. The maximum junction temperature of this integrated circuit should not exceed 150 °C.

Quad 2-input AND gate

8. Recommended operating conditions

Table 5.Operating conditions

Voltages are referenced to GND (ground = 0 V).

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V _{CC}	supply voltage		4.5	-	5.5	V
VI	input voltage		0	-	V _{CC}	V
V _{IH}	HIGH-level input voltage		2.0	-	-	V
V _{IL}	LOW-level input voltage		-	-	0.8	V
I _{OH}	HIGH-level output current		-15	-	-	mA
l _{ol}	LOW-level output current		-	-	20	mA
$\Delta t / \Delta V$	input transition rise and fall rate		0	-	5	ns/V
T _{amb}	ambient temperature	in free air	-40	-	+85	°C

9. Static characteristics

Table 6. Static characteristics

Symbol	Parameter	Conditions		25 °C			–40 °C to +85 °C		Unit
				Min	Тур	Max	Min	Max	
V _{IK}	input clamping voltage	$V_{CC} = 4.5 \text{ V}; \text{ I}_{IK} = -18 \text{ mA}$		-1.2	-0.9	-	-1.2	-	V
V _{OH}	HIGH-level output voltage	$\label{eq:V_CC} \begin{array}{l} V_{CC} = 4.5 \; V; \; I_{OH} = -15 \; mA; \\ V_{I} = V_{IL} \; or \; V_{IH} \end{array}$			2.9	-	2.5	-	V
V _{OL}	LOW-level output voltage	$V_{CC} = 4.5 \text{ V}; \text{ I}_{OL} = 20 \text{ mA};$ $V_{I} = \text{V}_{IL} \text{ or } \text{V}_{IH}$		-	0.35	0.5	-	0.5	V
l _l	input leakage current	/ _{CC} = 5.5 V; V _I = GND or 5.5 V		-	±0.01	±1.0	-	±1.0	μΑ
I _{OFF}	power-off leakage current	V_{CC} = 0 V; V_{I} or $V_{O} \leq 4.5$ V		-	±5.0	±100	-	±100	μΑ
I _{CEX}	output high leakage current	HIGH-state; $V_0 = 5.5 V$; $V_{CC} = 5.5 V$; $V_1 = GND$ or V_{CC}			5.0	50	-	50	μΑ
lo	output current	$V_{CC} = 5.5 \text{ V}; V_{O} = 2.5 \text{ V}$	[1]	-50	-75	-180	-50	-180	mA
I _{CC}	supply current	V_{CC} = 5.5 V; V_{I} = GND or V_{CC}		-	2	50	-	50	μΑ
ΔI _{CC}	additional supply current	per input pin; V_{CC} = 5.5 V; one input at 3.4 V; other inputs at V _{CC} or GND	[2]	-	0.25	500	-	500	μA
CI	input capacitance	$V_{I} = 0 V \text{ or } V_{CC}$		-	3	-	-	-	pF

[1] Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

[2] This is the increase in supply current for each input at 3.4 V.

Quad 2-input AND gate

10. Dynamic characteristics

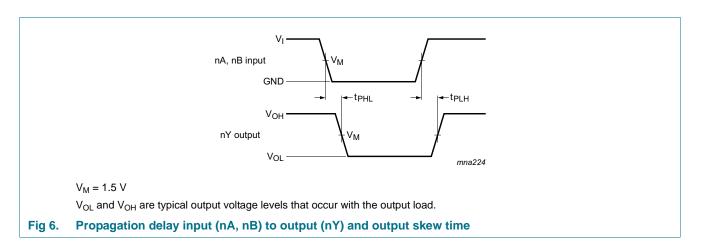
Table 7. Dynamic characteristics

GND = 0 V; for test circuit, see <u>Figure 7</u>.

Symbol	Parameter	ter Conditions		; V _{CC} =	5.0 V	−40 °C to +85 °C; V _{CC} = 5.0 V ± 0.5 V		Unit
			Min	Тур	Max	Min	Max	
t _{PLH}	LOW to HIGH propagation delay	nA, nB to nY; see <u>Figure 6</u>	1.0	2.4	3.4	1.0	4.0	ns
t _{PHL}	HIGH to LOW propagation delay	nA, nB to nY; see <u>Figure 6</u>	1.0	1.9	2.8	1.0	3.0	ns
t _{sk(o)}	output skew time	[1]	-	0.4	0.5	-	0.5	ns

[1] Skew between any two outputs of the same package switching in the same direction. This parameter is guaranteed by design.

11. Waveforms



5 of 14

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Quad 2-input AND gate

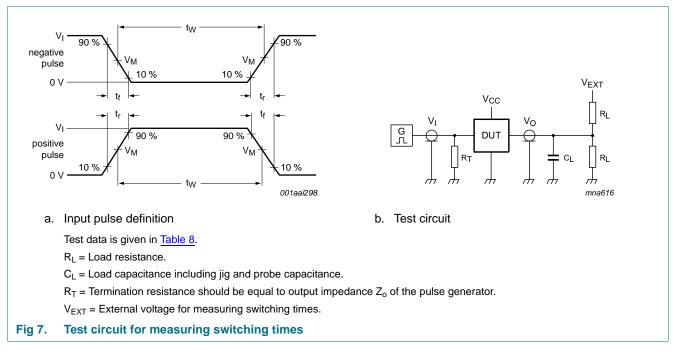


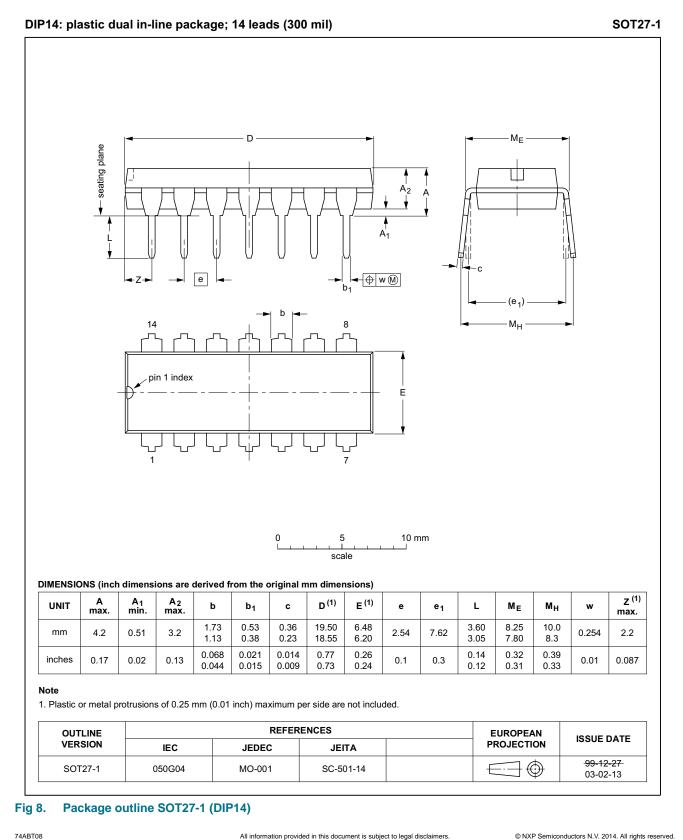
Table 8. Test data

Input			Load	V _{EXT}		
VI	f _i	t _W	t _r , t _f	CL	RL	t _{PHL} , t _{PLH}
3.0 V	1 MHz	500 ns	≤ 2.5 ns	50 pF	500 Ω	open

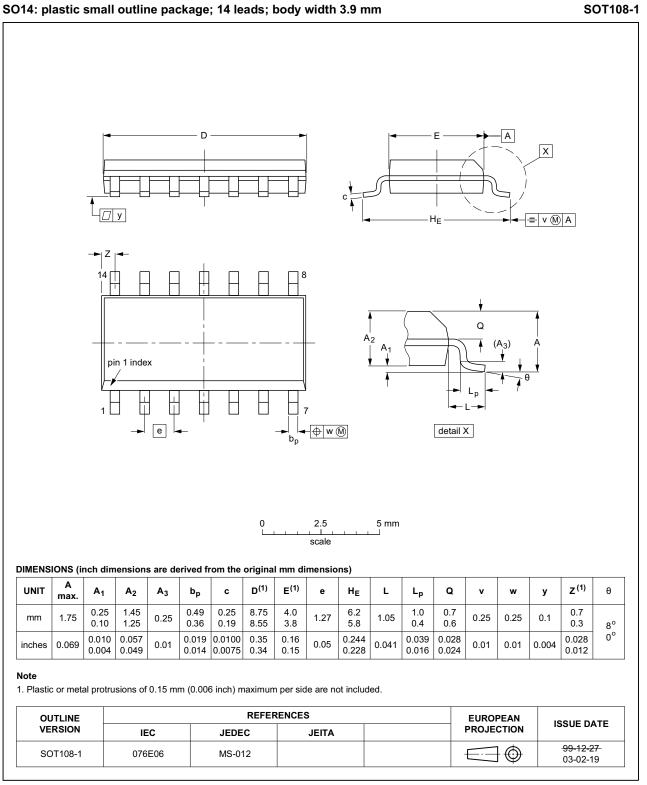
6 of 14

74ABT08 Quad 2-input AND gate

12. Package outline



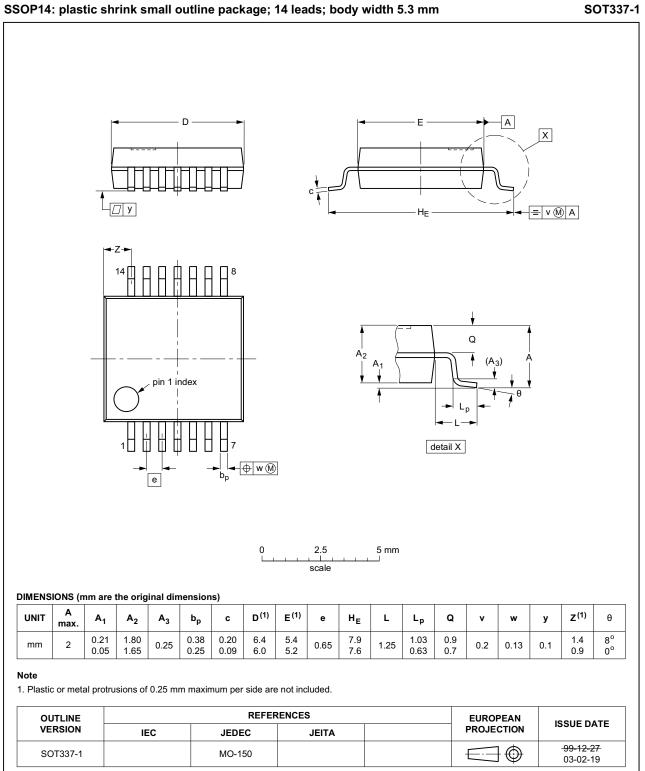
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SO14: plastic small outline package; 14 leads; body width 3.9 mm

Package outline SOT108-1 (SO14) Fig 9.

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SSOP14: plastic shrink small outline package; 14 leads; body width 5.3 mm

Fig 10. Package outline SOT337-1 (SSOP14)

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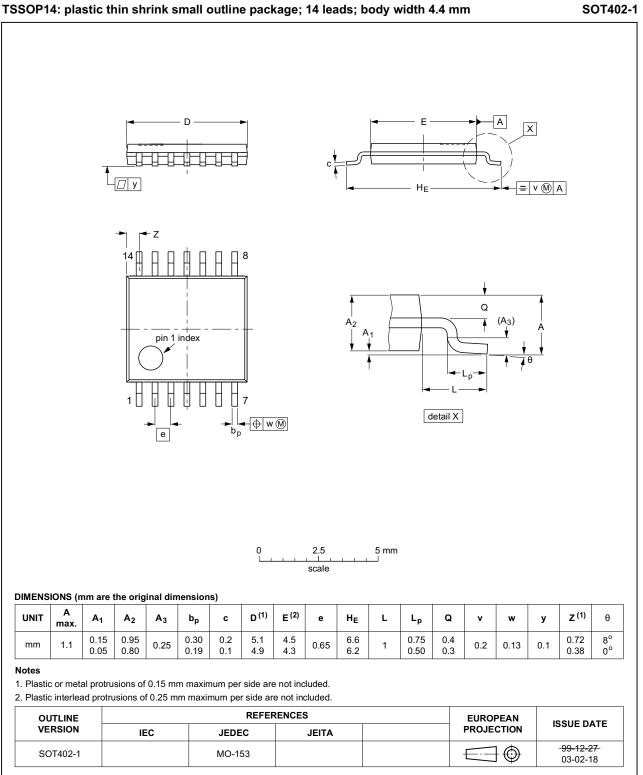


Fig 11. Package outline SOT402-1 (TSSOP14)

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13. Abbreviations

Table 9. Abbreviations				
Acronym	Description			
BiCMOS	Bipolar Complementary Metal-Oxide Semiconductor			
DUT	Device Under Test			
ESD	ElectroStatic Discharge			
НВМ	Human Body Model			
ММ	Machine Model			

14. Revision history

Table 10.Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
74ABT08 v.2	20140314	Product data sheet	-	74ABT08 v.1
Modifications:	 The format of this data sheet has been redesigned to comply with the new identity guidelines of NXP Semiconductors. 			
	 Legal texts have 	ave been adapted to the new c	ompany name where	e appropriate.
74ABT08 v.1	19950918	Product specification	-	-

15. Legal information

15.1 Data sheet status

Document status[1][2]	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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74ABT08

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74ABT08

17. Contents

1	General description 1
2	Features and benefits 1
3	Ordering information 1
4	Functional diagram 2
5	Pinning information 2
5.1	Pinning 2
5.2	Pin description 3
6	Functional description 3
7	Limiting values 3
8	Recommended operating conditions 4
9	Static characteristics 4
10	Dynamic characteristics 5
11	Waveforms 5
12	Package outline 7
13	Abbreviations 11
14	Revision history 11
15	Legal information 12
15.1	Data sheet status 12
15.2	Definitions 12
15.3	Disclaimers
15.4	Trademarks 13
16	Contact information 13
17	Contents 14

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